

# Improvement of Carrier Concentration of As-doped BaSi<sub>2</sub> Grown by Molecular Beam Epitaxy

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## Introduction

Barium disilicide (BaSi<sub>2</sub>) is one of the suitable materials for thin film solar cells due to its electrical and optical properties [1]. Currently, one of the challenges in realizing the high performing BaSi<sub>2</sub> homojunction solar cells is the fabrication of high-quality n-type BaSi<sub>2</sub> layer [1]. Previously, the fabrication and improvements of its photoresponsivity of n-type As-doped BaSi<sub>2</sub> thin film has been demonstrated grown by molecular beam epitaxy (MBE) using GaAs as the source of arsenic doping [2,3]. However, the carrier concentration is not well controlled. In our latest experiments, the activation ratio of doped arsenic atoms is quite low, approximately around 5 – 10%. In this study, the Ba-to-Si deposition rate ratio ( $R_{Ba}/R_{Si}$ ) is increased in hope to increase more silicon vacancy ( $V_{Si}$ ) for arsenic to occupy.

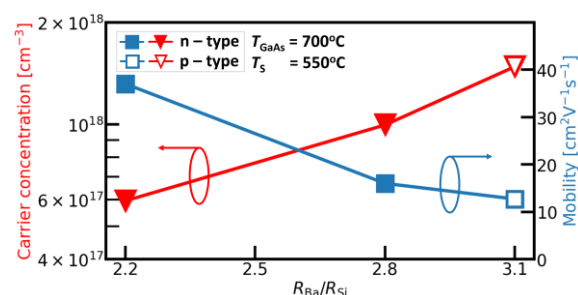
## Experimental Method

In this work, As-doped BaSi<sub>2</sub> films were grown on top of p-Si(111) substrates using MBE method. The steps of thin-film growth are carried out as in the previous report [2]. The substrate temperature ( $T_s$ ) during growth was set to 550°C and GaAs crucible temperature ( $T_{GaAs}$ ) was varied between 700°C – 750°C. The  $R_{Ba}/R_{Si}$  was varied between 2.2 – 3.1. The carrier concentration and mobility were measured at room temperature using Van der Pauw method. The photoresponsivity was measured using a xenon lamp and a 25-cm focal length single monochromator (Bunko Keiki SM-1700A and RU-60N). SIMS measurements are carried out to identify the arsenic concentration incorporated into the grown films.

## Results and Discussion

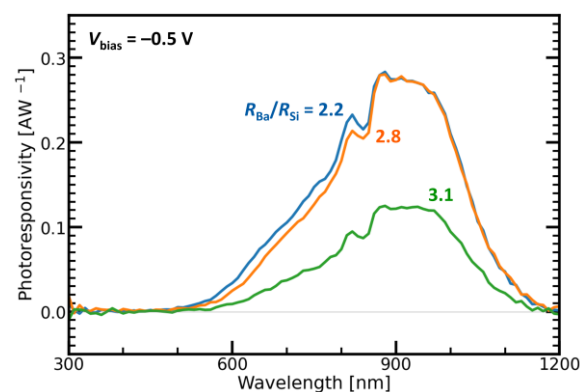
The trend of carrier properties against  $R_{Ba}/R_{Si}$  is shown in Fig.1. As can be seen, the carrier concentration increased from  $5.95 \times 10^{17} \text{ cm}^{-3}$

( $R_{Ba}/R_{Si} = 2.2$ ) to  $9.96 \times 10^{17} \text{ cm}^{-3}$  ( $R_{Ba}/R_{Si} = 2.8$ ). This can be interpreted as more arsenic is electronically activated through occupying  $V_{Si}$  sites. The electron mobility shows the opposite trend of carrier concentration, meaning the dopants acting as scatterer [4]. However, at  $R_{Ba}/R_{Si} = 3.1$ , the observed carrier type was p-type.



**Figure 1.** Carrier properties vs  $R_{Ba}/R_{Si}$ . Red marker denotes carrier concentration while blue marker denotes Hall mobility measured at room temperature.

The photoresponsivity spectra in reverse bias mode ( $V_{bias} = -0.5\text{V}$ ) are shown in Fig. 2. The photoresponsivity at  $R_{Ba}/R_{Si} = 2.2$  and 2.8 are quite similar while significantly lower photoresponsivity peaks are observed for  $R_{Ba}/R_{Si} = 3.1$  sample.



**Figure 2.** Photoresponsivity of grown BaSi<sub>2</sub> films at  $R_{Ba}/R_{Si} = 2.2$ , 2.8, and 3.1 measured at  $V_{bias} = -0.5\text{V}$ .

## Reference

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